

***Information Disclosure Statement***

1. The information disclosure statement (IDS) submitted on 10/29/2007 was filed after the mailing date of the instant application on 07/16/2003. The submission is in compliance with the provisions of 37 CFR 1.97. Accordingly, the information disclosure statement has been considered by the examiner.

**EXAMINER'S AMENDMENT**

1. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it **MUST** be submitted no later than the payment of the issue fee.

2. Authorization for this examiner's amendment was given in a telephone interview with Attorney Kenneth Springer on 12/23/2008.

Claim 36 has been amended as follows:

Line 4, after "substrate", --for receiving a gate signal-- has been inserted;

line 14, "are adapted to receive a" has been deleted and --include means for receiving the-- has been inserted. Thus, the last line of this claim recites, "wherein the first and second signal lines include means for receiving the same gate signal".

3. These amendments were made in the above telephone interview in order to structurally define these claims over all the prior art of record. Support for the above recited structure is found in paragraph 72 of the specification herein.

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4. In addition, the title has been amended to be more descriptive of the invention as follows: "LCD having repair lines wherein first and second signal lines include means for receiving the same gate signal thereon are formed on a TFT insulating substrate".

### **Reasons for Allowance**

5. The following is an examiner's statement of reasons for allowance: None of the prior art of record, nor uncovered to date shows or discloses the now claimed features in which a TFT substrate comprises an insulating substrate having first, second and third signal lines in which the first signal line includes a gate electrode...for receiving a gate signal; and in which the third signal line overlaps the first and second signal lines; and "wherein the first and second signal lines include means for receiving the same gate signal". It is agreed that the patents to Kim (US 5,969,779), Kawate (US 4,368,523) and Wakai (US 5,327,001) all applied in the last Office Action fail to show at least the structural feature of "the first and second signal lines include means for receiving the same gate signal" as now recited. As such, Claim 36 and dependent Claims 37-41 are deemed allowable as presently advised.

6. Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Any inquiry concerning this communication or earlier communications from the examiner should be directed to JOHN HEYMAN whose telephone number is (571)272-5730. The examiner can normally be reached on 7:30am - 4:00pm.

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If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, David Nelms can be reached on 571- 272-1787. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

/J. H./  
Examiner, Art Unit 2871

/David Nelms/  
Supervisory Patent Examiner, Art Unit 2871